

Resource Summary Report

Generated by RRID on Aug 6, 2026

FEI: Meridian WS-DP System for Semiconductors

RRID:SCR_019890

Type: Tool

Proper Citation

FEI: Meridian WS-DP System for Semiconductors (RRID:SCR_019890)

Resource Information

URL: <https://www.fei.com/products/efa/meridian-ws-dp-for-semiconductors/>

Proper Citation: FEI: Meridian WS-DP System for Semiconductors (RRID:SCR_019890)

Description: Electrical failure analysis system for semiconductors that enables faster defect localization by using production testers, load boards, and probe cards.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Meridian WS-DP System for Semiconductors

Resource ID: SCR_019890

Alternate IDs: Model_Number_Meridian_WS_DP

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190648+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Meridian WS-DP System for Semiconductors.

No alerts have been found for FEI: Meridian WS-DP System for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.